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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/647,472	08/26/2003	Lawrence M. Burns	1875.3770001	2309
26111 STEDNE VES	7590 10/12/200	EXAMINER		
STERNE, KESSLER, GOLDSTEIN & FOX P.L.L.C. 1100 NEW YORK AVENUE, N.W.			HOLLINGTON, JERMELE M	
WASHINGTON, DC 20005			ART UNIT	PAPER NUMBER
			2829	
		,	MAIL DATE	DELIVERY MODE
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			10/12/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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		Application No.	Applicant(s)
Office Action Summary		10/647,472	BURNS ET AL.
		Examiner	Art Unit
		Jermele M. Hollington	2829
Period fo	The MAILING DATE of this communication ap or Reply	pears on the cover sheet wit	h the correspondence address
WHI0 - Exte afte - If N0 - Failt Any	HORTENED STATUTORY PERIOD FOR REPLICATION OF THE MAILING DEPLICATION OF THE	DATE OF THIS COMMUNIC 136(a). In no event, however, may a re will apply and will expire SIX (6) MONT te, cause the application to become ABA	ATION. ply be timely filed THS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).
Status			
1)[🛛	Responsive to communication(s) filed on 16 J	July 2007.	
2a)⊠	This action is FINAL . 2b) ☐ This	s action is non-final.	
3)	Since this application is in condition for alloward closed in accordance with the practice under	· ·	·
Disposit	tion of Claims		
5)□ 6)⊠ 7)⊠	Claim(s) 1-20 is/are pending in the application 4a) Of the above claim(s) is/are withdra Claim(s) is/are allowed. Claim(s) 1,2,4,5,11,12,14 and 15 is/are rejected Claim(s) 3, 6-10, 13 and 16-20 is/are objected Claim(s) are subject to restriction and/or claim(s) are subject to restriction and/or claim(s) are subject to restriction.	ed. d to.	
Applicat	tion Papers		
9)	The specification is objected to by the Examin	er.	
10)	The drawing(s) filed on is/are: a)☐ acc		
	Applicant may not request that any objection to the		
11)	Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the E		
Priority	under 35 U.S.C. § 119		,
a)	Acknowledgment is made of a claim for foreign All b) Some * c) None of: 1. Certified copies of the priority documen 2. Certified copies of the priority documen 3. Copies of the certified copies of the priority application from the International Burea See the attached detailed Office action for a list	nts have been received. nts have been received in Apority documents have been au (PCT Rule 17.2(a)).	oplication No received in this National Stage
2) 🔲 Not	ice of References Cited (PTO-892) ice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s	ummary (PTO-413))/Mail Date vformal Patent Application
	ormation Disclosure Statement(s) (PTO/SB/08) per No(s)/Mail Date	6) Other:	_·

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DETAILED ACTION

Response to Arguments

- 1. Applicant's arguments filed February 16, 2007 have been fully considered but they are not persuasive.
- a) The applicants' argue: "However, the Examiner fails to identify what process-dependent parameter the on-chip signal 26 allegedly represents. In the Response to Arguments section of the Office Action, the Examiner appears to argue that the term "process-dependent" recited in claims 1 and 11 should be ignored."

In response to the above argument, the examiner believes a miscommunication occur from the last office action. The examiner is not ignoring the term "process-dependent". The examiner is expressing using the word "parameter" gives a broad arbitrary value to the term "process-dependent". Further, the examiner disagrees with the argument "fails to identify what process-dependent parameter...represents." In the claims 1 and 11, it states: "...at least one digitized sense signal represents a corresponding process-dependent parameter..." Base on the claimed language, the process-dependent parameter is at least one digitized sense signal, which the examiner used on chip signal 26 based on col. 4, line 62-col. 5, line 27, in col. 6, line 34-col. 7, line 25 and in col. 9, lines 16-34, discuss comparing the on-chip signal to the set signal from an external source to determine if the signal are the same when the semiconductor device is being tested. Therefore, the examiner believes that Adams suggests what is being claimed.

b) The applicants' further argue: "In addition, the Examiner states that Adams discloses "the at least one determined analog value is utilized to configure an operational portion of the integrated circuit (10) to account for the measured process-dependent parameter." (Office

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Action, p. 3). However, the Examiner has not identified any passages within Adams to support this assertion."

In response to the above argument, the examiner would like the applicants to see col. 4, lines 50-61, where is partially states: "...a test circuit 30 is provided on-chip for evaluating a signal characteristic of an on-chip signal 26, such as, for example, the analog signal..." Also col. 5, lines 28-40 and col. 6, lines 34-51 suggest the claimed invention. Therefore, the examiner believes that Adams suggests what is being claimed

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 1-2, 4-5, 11-12 and 14-15 are rejected under 35 U.S.C. 102(b) as being anticipated by Adams et al (6163862).

Regarding claims 1 and 11, Adams et al disclose [see Figs. 1 and 3] a system for monitoring an integrated circuit chip (semiconductor device 10), comprising: means for receiving (test circuit 30 and sense amplifier 18) at least one digitized sense signal (on-chip signal 26) from the integrated circuit chip (10), whereby the at least one digitized sense signal (26) represents a corresponding process-dependent parameter within the integrated circuit chip (10); and means for determining (test circuit 30) an analog value for the at least one process-

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dependent circuit parameters from the corresponding at least one digitized signal (26); wherein the process-dependent parameter is measured within a process monitor portion (sense amplifier 18) of the integrated circuit (10) and the at least one determined analog value is utilized to configure an operational portion of the integrated circuit (10) to account for the measured process-dependent parameter.

Regarding claims 2 and 12, Adams et al disclose the means for receiving (30) and the means for determining (30) are positioned external of the integrated circuit chip (10).

Regarding claims 4 and 14, Adams et al disclose the means for determining (30) comprises means for calculating the at least one value from the at least one digitized signal (26).

Regarding claims 5 and 15, Adams et al disclose the at least one digitized sense signal (26) represents a gate-to-source threshold voltage of a transistor [shown in Fig. 1A] fabricated on the integrated circuit chip (10).

Conclusion

- 4. Claims 3, 6-10, 13 and 16-20 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
- 5. The following is a statement of reasons for the indication of allowable subject matter: regarding claims 3 and 13, the reason for allowance of the claims is a system and method for monitoring an IC chip comprises, in combination with other limitations, means for determining comprises means for retrieving the at least one value from a look-up table using the at least on digitized signal.

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Regarding claims 6-10 and 16-20, the reason for allowance of the claims is a system and method for monitoring an IC chip comprises, in combination with other limitations, the at least one digitized sense signal includes a plurality of digitized sense signals that represent a plurality of the following: a transconductance parameter of a transistor fabricated on the integrated circuit chip; a sheet resistance of a resistor fabricated on the integrated circuit chip; a temperature of the integrated circuit chip; and a power supply voltage on the integrated circuit chip.

Base on the arguments above, the following is being applied.

6. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jermele M. Hollington whose telephone number is (571) 272-1960. The examiner can normally be reached on M-F (9:00-4:00 EST) First Friday Off.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Ha Nguyen can be reached on (571) 272-1678. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Jermele M. Hollington Primary Examiner Art Unit 2829

JMH October 10, 2007